

Developments for serial power applications

Laura Gonella

Report on RD53 powering working group

ACES workshop

08/03/2016

Introduction

- R&D on serial powering ongoing for more than 10 years in ATLAS
 - Leading institutes
 - Uni Bonn for pixels
 - RAL, UPenn, BNL for strips
 - Serial powering proven to be a feasible and reliable powering scheme for trackers at the HL-LHC
 - The current scalability brings significant advantages in terms of material reduction and power efficiency
- Serial powering is the baseline powering scheme for pixel detectors at the HL-LHC (ATLAS and CMS)

RD53 powering working group

- RD53 established a powering working group in 2015
- Main focus of the group is twofold
 - Input and discussions with chip designers about powering aspects for the future pixel chips in 65nm
 - Exchange of experiences and concepts with powering schemes between the different experiments, **esp. serial powering but not exclusively**
- Meetings are quarterly
 - 2 meetings in 2015 plus a special meeting on serial powering simulations in 2016

The screenshot shows the agenda for the 'Serial powering working group' meeting on Thursday, 10 December 2015, from 14:00 to 16:15 (Europe/Zurich) at CERN (14-4-010). The agenda is as follows:

Time	Topic	Speakers	Attachments
14:00 - 14:10	Introduction and organization of future serial power meetings	10'	
14:10 - 14:25	serial powering at Bonn	15'	Serial_power....
14:25 - 14:40	Serial powering at CERN	15'	PP2_v2.pdf
14:40 - 14:55	Serial powering at Florence	15'	SP-Firenze-1...
14:55 - 15:10	serial power at Liverpool	15'	serial-power1..., serial-power1...
15:10 - 15:25	Serial power at Glasgow	15'	SerialPowerin..., SerialPowerin...
15:25 - 15:40	DCS chip for serial powering	15'	151210_Seria...
15:40 - 15:55	Shunt-LDO in 65nm	15'	Shunt-LDO-R..., Shunt-LDO-R...
15:55 - 16:15	Round table and AOB	20'	

Serial powering configurations

■ In module SP

- Each module builds its own SP chain
- Independent module power as in voltage based powering schemes
- Number of chips in module defines the reduction factor n
- Sensor connected to a few volts different ground

■ Across module SP

- SP chain made of n modules defined by design of local support structures (ATLAS pixels: up to $n = 8 - 10$)
- Modules/sensors grounds differ inside the SP chain
- Option investigated so far by ATLAS pixels

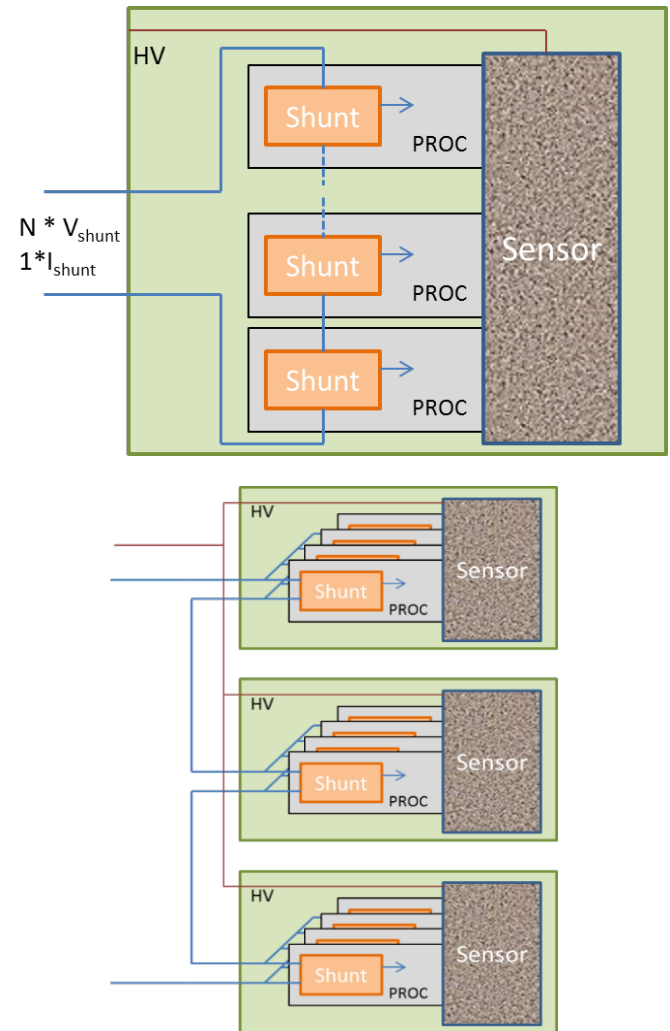
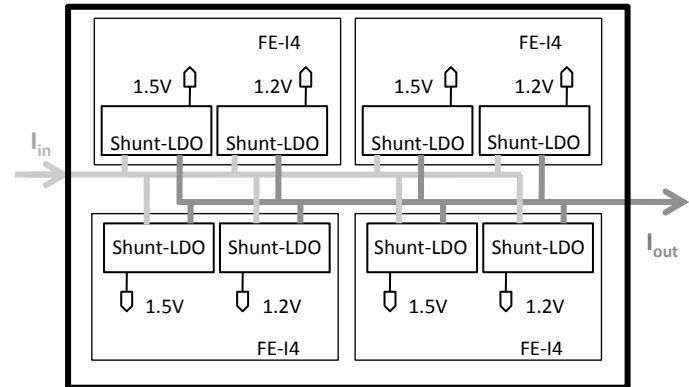


Figure from J. Christiansen

Enabling technologies

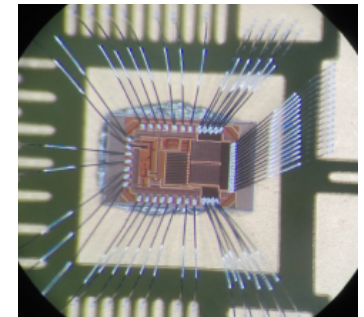
- **Shunt-LDO** regulator
 - 2 integrated in the FE-I4 chip
- **Redundancy** and module bypass
 - Parallel connection of all regulators on module
 - **PSPP** chip as part of DCS system
- **AC-coupling**
 - FE-I4 cmd and data DC-balanced
 - Self-biased FE-I4 RX inputs
- **HV distribution concepts** with return referenced to local module ground via high resistive path, or to current return

Current distribution on module

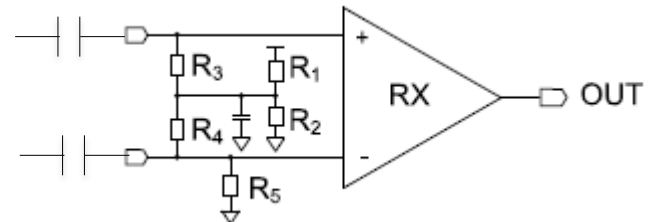


PSPP chip

Picture from N. Lehmann



FE-I4 AC-coupled LVDS link



Shunt-LDO regulator

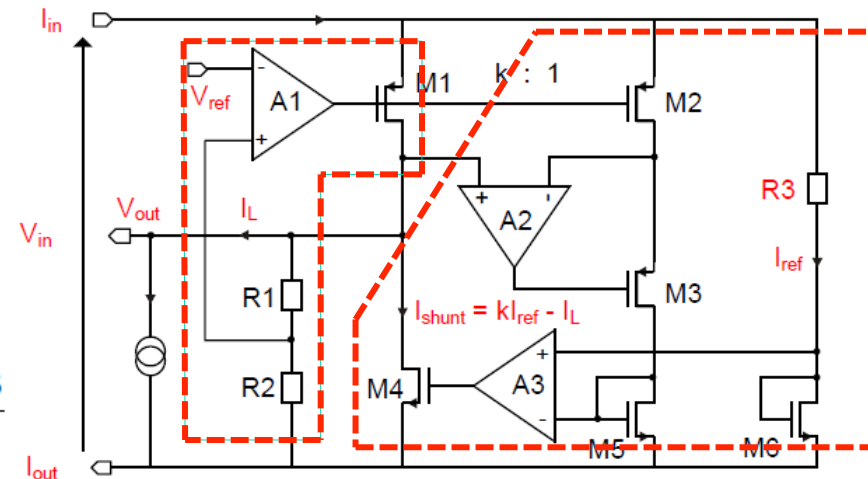
- Idea and design by M. Karagounis (Hochschule Hamm-Lippstadt)

- Voltage regulation loop (**LDO**) → constant $V_{out} = 2V_{ref}$
- Current regulation loop (**shunt**) → keeps current through the regulator constant

- Ohmic input characteristics $R_{in} \approx \frac{V_{in}}{I_{in}} \approx \frac{R3}{k}$

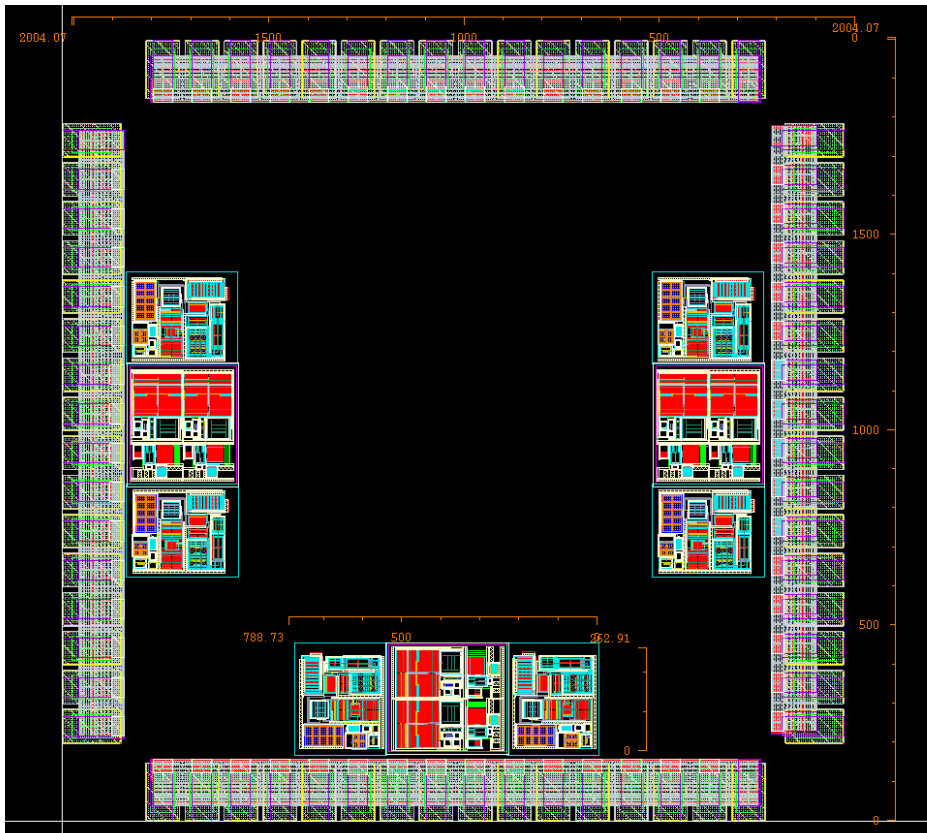
- Shunt-LDO features

- Robust design against process variation and mismatch for safe parallel operation
- Parallel operation of regulators with different output voltages and shunting capabilities possible
- Ability to shunt extra current
- Different working modes for current and voltage based powering



Upcoming: shunt-LDO prototype in 65nm

- 1:1 copy of the design of the Shunt-LDO in FE-I4 (not yet designed for 65nm chip specs)
- Submitted last week



Testchip – Size

2 mm x 2 mm

Testchip - Content

3 regulator incl. biasing

Pad – Count

4 x 16 with 100 μm pitch

Area per Regulator:

800 μm x 400 μm

Pads per Regulator:

5 x input current

5 x shunt current

5 x output voltage

1 x reference voltage

1 x biasing voltage

1 x internal resistor con.

1 x external resistor con.

1 x shunt-circuitry supply

Pixel Serial Powering Protection (PSPP) chip

- Work done at Uni Wuppertal, design by L. Puellen
- Module bypass scheme integrated into DCS system
- PSPP chip loaded on module flex, connected in parallel to the module
- Features:
 - Autonomous fault detection
 - Addressable power control to switch on/off selected modules
 - ADC could be used to measure HV, sensor leakage current, temperature
- PSPP chip services: I2C and power → 3 lines per SP chain
- Two prototypes already existing → working principle demonstrated

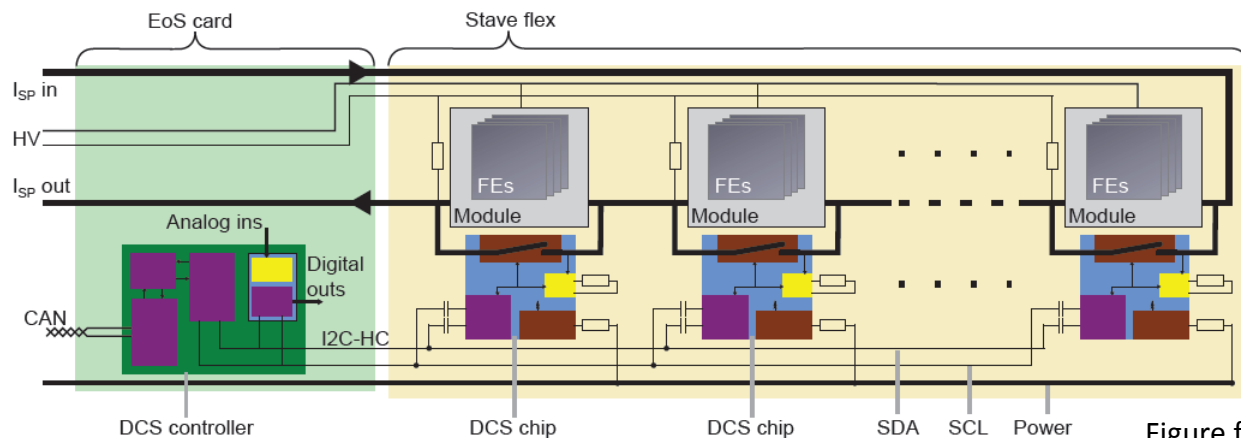
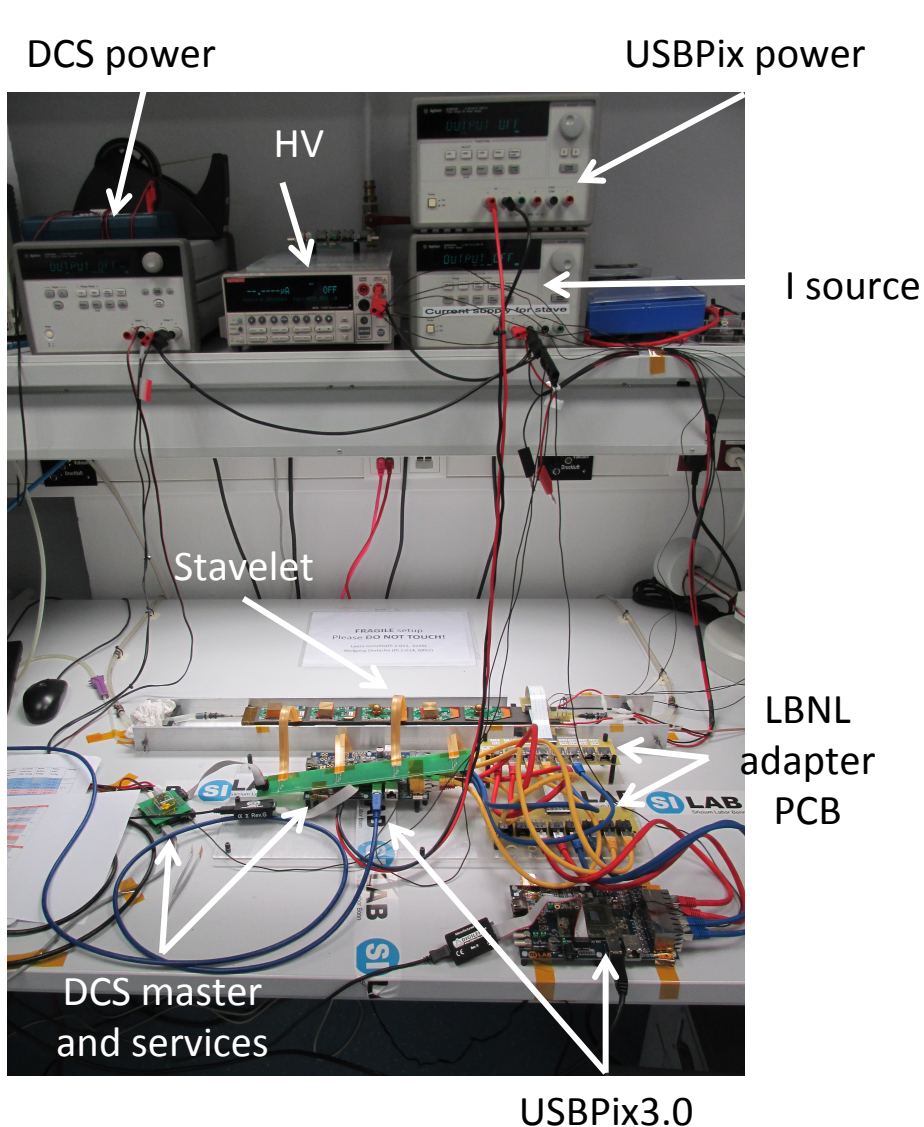


Figure from L. Puellen

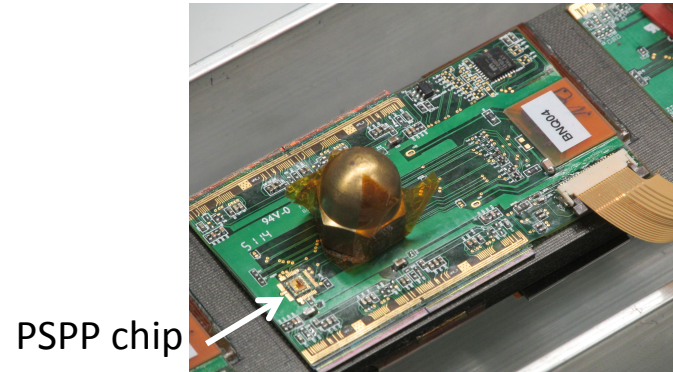
Serial powering systems with FE-I4

- Several serial powering systems are in operation/development to study system aspects
 - Uni Bonn: 6 FE-I4 quad modules on a stavelet, partially equipped with PSPP chips
 - LBNL: 3 FE-I4 quad modules on a stavelet
 - Uni Liverpool: 4 FE-I4 quad modules on PCBs in one SP chain
 - Uni Glasgow and INFN Florence: SP chain of FE-I4 single chip modules on PCBs
 - More systems in preparation at CERN and Uni Oklahoma
- Overall performance is good, no significant differences observed with respect to voltage based powering schemes

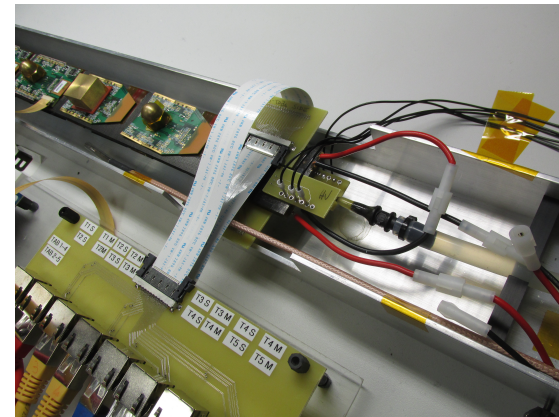
Serial powering stavelet in Bonn



Quad module



End-Of-Stave



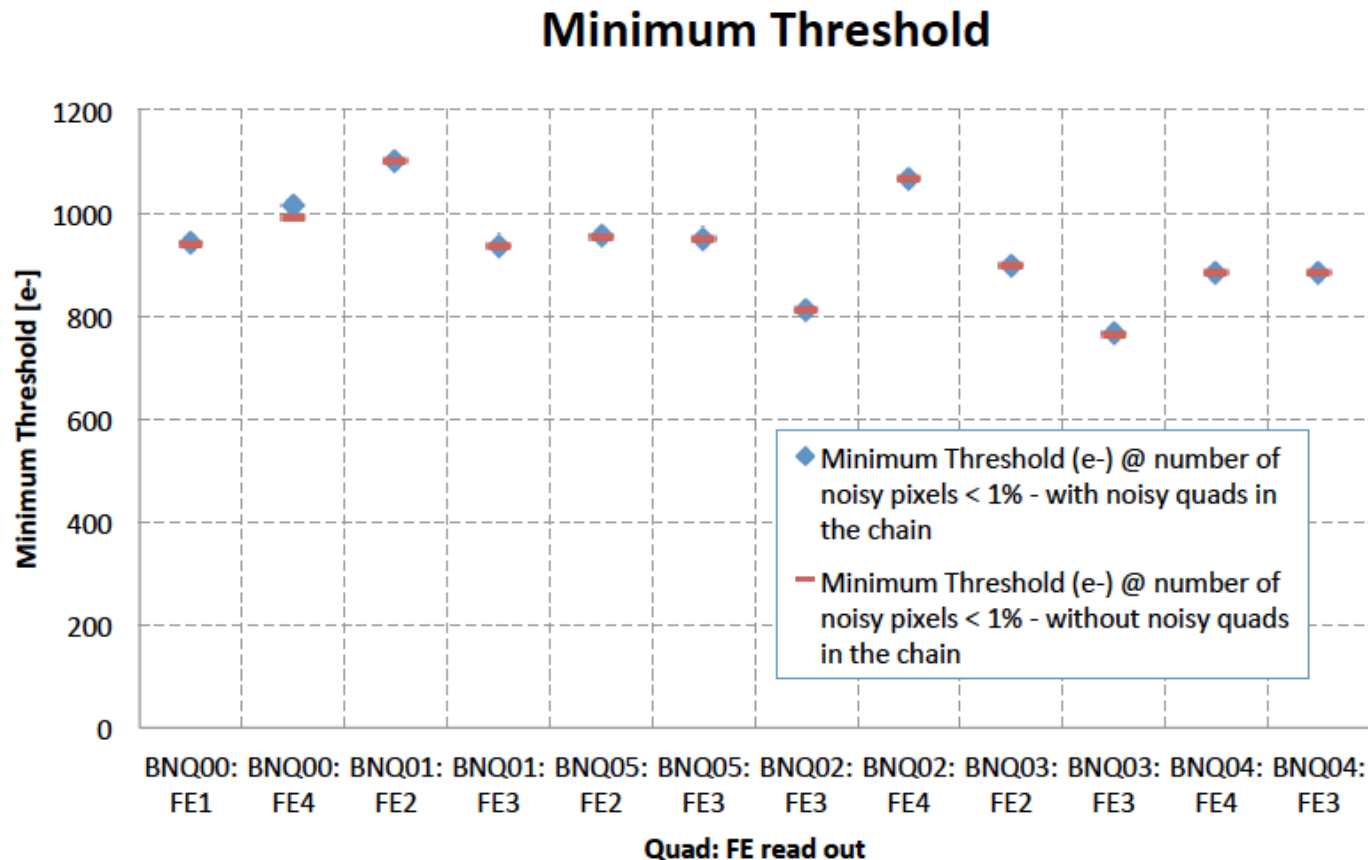
All measurements and plots in the following slides done by V. Filimonov

Minimum threshold operation

- Starting point: 6 quad modules tuned to standard threshold values (i.e. 1500e⁻ threshold, 10TOT @16ke⁻)
- Lower the global threshold (GDAC) in steps
- At each step
 - Perform noise occupancy scan (10⁷ triggers, 25ns each)
 - Mask pixels with a noise hit probability (NOcc) > 10⁻⁷
- When the number of masked pixels reaches 1% stop the scan
 - Leave the FE noisy and continue with the other FEs
 - Increase the global threshold (GDAC +1) and continue with the other FEs

Results of minimum threshold searches

- FEs can be operated at thresholds as low as $\sim 800e^-$
- Noisy FEs in the chain do not affect the performance of the other FEs

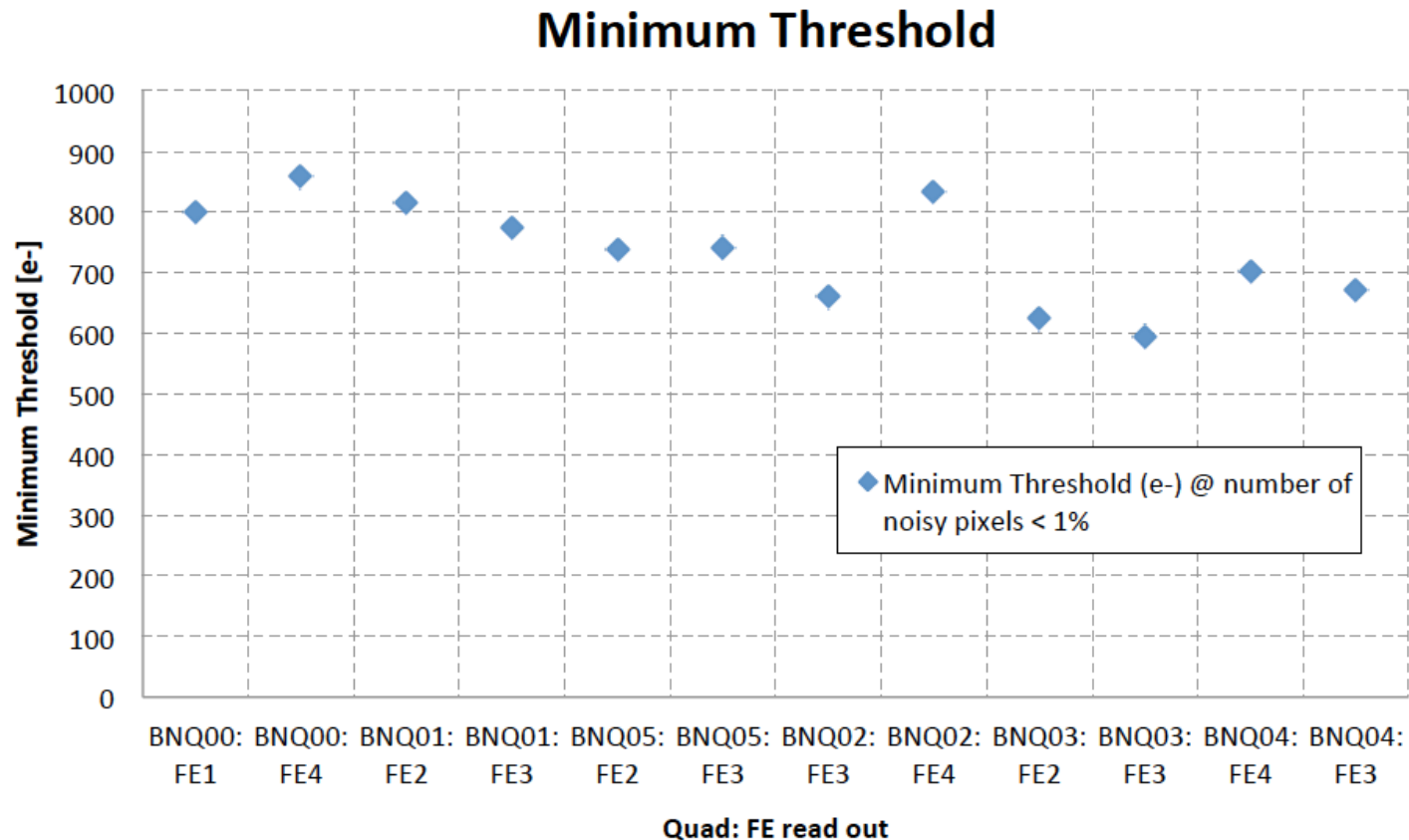


Improved minimum threshold search

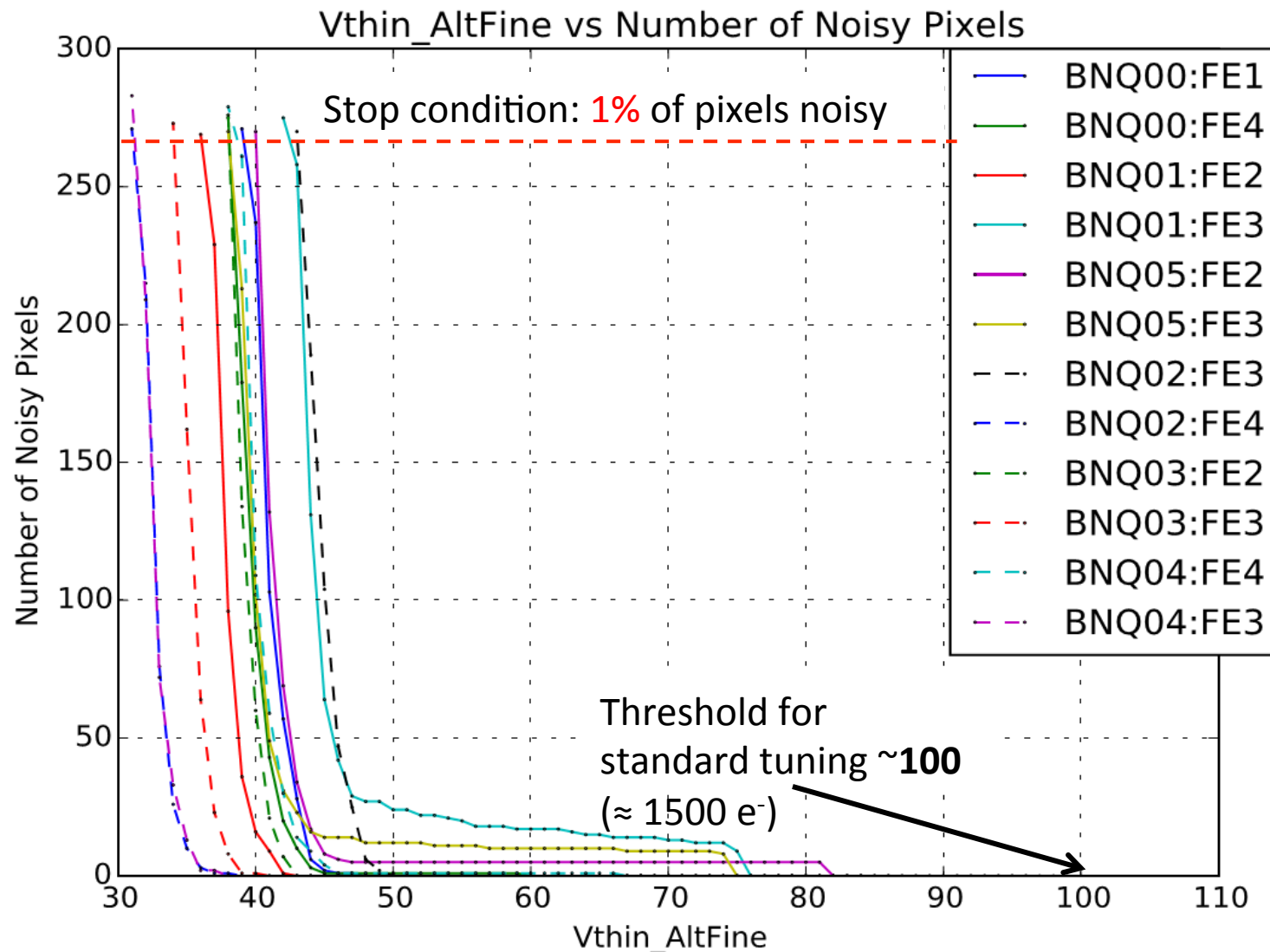
- Starting point: 6 quad modules tuned to standard threshold values (i.e. 1500e⁻ threshold, 10TOT @16ke⁻)
- Lower the global threshold (GDAC) in steps
- At each step, tune the local threshold (TDAC), i.e. increase the threshold of noisy pixels
 - Perform noise occupancy scan (10^7 triggers sent, 25ns each)
 - Mask pixels with NOcc > 10^{-7} or TDAC at maximum
- When the number of masked pixels reaches 1% stop the scan
- Increase the global threshold (GDAC +1) and continue with the other FEs

Results of improved minimum threshold searches

- FEs can be operated at thresholds below $\sim 800e^-$, down to $\sim 600e^-$

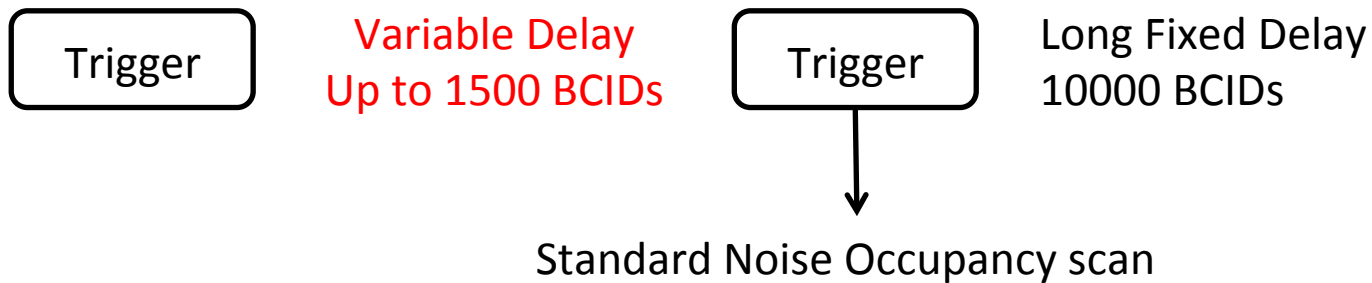


Results of improved minimum threshold searches



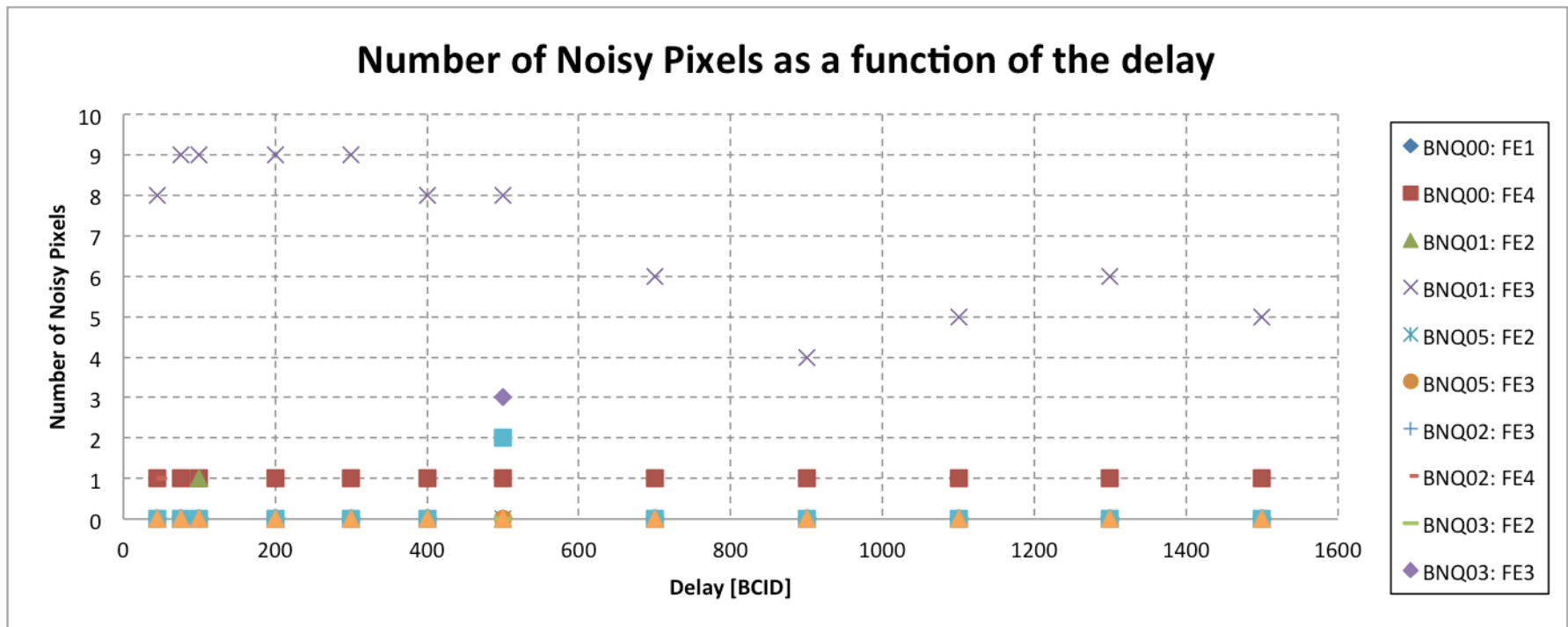
2-trigger scan: influence on NOcc

- Starting point: 6 quad modules tuned to minimum threshold
- Command pattern
 - Trigger multiplicity = 1
 - Long fix delay between repetitions



2-trigger scan: influence on NOcc

- No increase in the number of noisy pixels wrt. standard operation
- Lowest delay between triggers $\sim 45\text{BC}$. For lower values data errors \rightarrow needs to be investigated (observed also on direct power module)



Conclusion

- Powering for pixel detectors at the HL-LHC is challenging!
- Current ideas are based on long experience with serial powering of ATLAS pixel modules
 - Enabling technologies like shunt-LDO, module bypass scheme, AC-coupling data transmission etc. already developed and integrated in ATLAS pixel modules
 - Successfully built serial powered pixel systems based on FE-I3 and FE-I4 with similar performance as parallel powered systems
- More work needed in many areas (esp. off-stave)
 - Complete definition of the entire pixel powering scheme
 - Modularity, i.e. size of SP chains
 - Power, voltage and current requirements of chips resp. modules
 - Grounding and shielding concepts